

Notice of References Cited	Application/Control No. 10/802,207	Applicant(s)/Patent Under Reexamination HAN ET AL.	
	Examiner James A. Dudek	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0160568	08-2004	Kim et al.	349/156
	B	US-2003/0025868	02-2003	Hiroshima et al.	349/156
	C	US-6,724,458	04-2004	Kim et al.	349/156
	D	US-6,705,584	03-2004	Hiroshima et al.	349/156
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
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NON-PATENT DOCUMENTS

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	V	
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